

Notice of References Cited	Application/Control No. 10/791,926		Applicant(s)/Patent Under Reexamination HOCHENG ET AL.	
	Examiner Emmanuel S. Luk		Art Unit 1722	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,472,331	12-1995	Watkins, Brad H.	425/149
*	B	US-5,772,905	06-1998	Chou, Stephen Y.	216/44
*	C	US-2001/0022406	09-2001	Woodmansee et al.	264/40.5
*	D	US-2002/0097059	07-2002	Tartagni et al.	324/687
*	E	US-2003/0209817	11-2003	Lee et al.	264/1.1
*	F	US-2004/0009252	01-2004	Reichstein et al.	425/143
*	G	US-6,769,897	08-2004	Eppich et al.	425/151
*	H	US-2004/0238821	12-2004	Yang, Chien-Sheng	257/072
*	I	US-2005/0003036	01-2005	Nishimura et al.	425/135
*	J	US-2005/0084557	04-2005	Fueller et al.	425/170
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.